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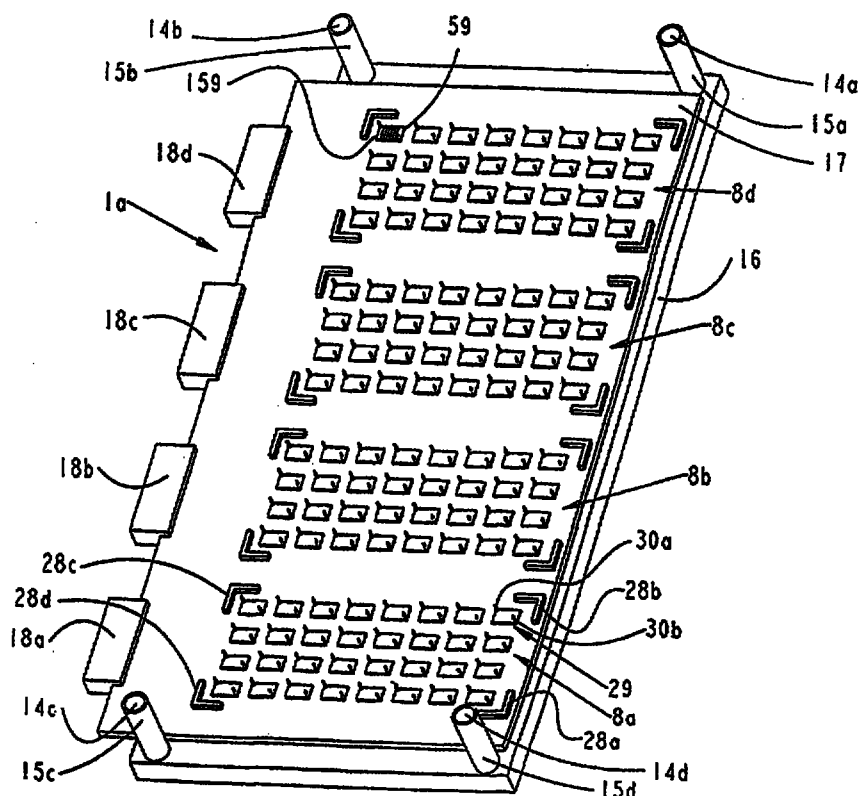
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(54) Title: SYSTEM TO SIMULTANEOUSLY TEST TRAYS OF INTEGRATED CIRCUIT PACKAGES

(57) Abstract

A test system for testing numerous parts simultaneously. A stack of test boards is provided in a test chamber. Each of the test boards has a region of contactors on it. To perform a test, trays are inserted between the boards in the stack and aligned with the regions of contactors. A mechanism is then activated to press the trays towards the boards, thereby making contact between the contactors and devices on the trays. The test system is described in conjunction with a burn-in oven. Processing time is reduced because individual handling of chips is significantly reduced.



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